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### **Product Change Notice (PCN)**

Subject: Wafer Fabrication Site Change for Listed Intersil ISL21060\* Products Publication Date: 4/3/2015 Effective Date: 7/3/2015

#### **Revision Description:**

Initial Release

#### **Description of Change:**

Wafer Fabrication Site Change for Listed Intersil ISL21060\* Products

#### Reason for Change:

This notice is to inform you that Intersil has qualified Intersil's Palm Bay, Florida facility for wafer fabrication of the listed C5 technology products. The process technology qualification activity is complete. The package related qualification and product validation activity is scheduled to complete July 2015.

#### Impact on fit, form, function, quality & reliability:

The product and site qualification plans are designed using JEDEC and other applicable industry standards to confirm there is no impact to form, fit, function, or interchangeability of the product. A summary of the qualification plan is included for reference. The qualification results will be available for review upon completion by request. The ICP Test Report for the Palm Bay fabrication facility is located on Intersil's Environmental web site under Material Sub-Group: "Silicon"; Material "die" and the PDF file is titled Intersil Corporation. http://www.intersil.com/en/support/environmental.html#WA;

#### **Product Identification:**

Product affected by this change is identifiable via Intersil's internal traceability system.

Qualification status: In progress, see attached Sample availability: 7/3/2015 Device material declaration: Available upon request

Questions or requests pertaining to this change notice, including additional data or samples, must be sent to Intersil within 30 days of the publication date.

For additional information regarding this notice, please contact your regional change coordinator (below)							
Americas: PCN-US@INTERSIL.COM	Europe: PCN-EU@INTERSIL.COM	Japan: PCN-JP@INTERSIL.COM	Asia Pac: PCN-APAC@INTERSIL.COM				

Appendix A - Affected Products List (see attached) Appendix B - Qualification Results (see attached)

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#### Appendix A:

ISL21060BFH620Z-TK	ISL21060BFH641Z-TK	ISL21060CFH630Z-TK
ISL21060BFH625Z-TK	ISL21060CFH620Z-TK	ISL21060CFH633Z-TK
ISL21060BFH630Z-TK	ISL21060CFH625Z-TK	ISL21060CFH641Z-TK

#### Appendix B:

Stress / Conditions	Duration	X5043S8IZ2.7AT1 Soicn	ISL60002DIH325Z S0T-23	ISL60002DIH310Z S0T-23	X9C103SIZT1 SOICN
Moisture Sensitivity Classification		N = 44 Acc = 0 L1 PBFREE	N = 44 Acc = 0 L1 PBFREE	N = 22 Acc = 0 L1 PBFREE	N = 44 Acc = 0 L1 PBFREE
High Temp Operating Life +125°C	1000 Hours	N = 234 Acc = 0	N = 160 Acc = 0	N/A	N = 156 Acc = 0
Unbiased HAST +130C / 85% RH	96 Hrs	N = 78 Acc = 0	N = 78 Acc = 0	N/A	N = 78 Acc = 0
Autoclave +121C / 100% RH	96 Hrs	N/A	N/A	N = 45 Acc = 0	N/A
Temp Cycle +150C / -65C	500 Cy	N = 78 Acc = 0	N = 78 Acc = 0	N = 45 Acc = 0	N = 78 Acc = 0
Biased HAST +130C / 85% RH	96 Hrs	N = 78 Acc = 0	N = 99 Acc = 0	N/A	N = 78 Acc = 0
High Temperature Storage T <sub>A</sub> = +150C	1000 Hrs	N = 78 Acc = 0	N = 78 Acc = 0	N = 45 Acc = 0	N = 78 Acc = 0

Qualification Completed/Passed Qualified by Extension